



David Tien is presently a Product Marketing Director in the Materials and Structural Analysis Division of Thermo Fisher Scientific. He has recently taken responsibility for the Wafer Dualbeam and SEM product lines within the physical failure analysis group of the semiconductor business unit. Prior to his new role, he was responsible for various electrical failure analysis product lines including Lock-in Thermography and Circuit Editing where he worked with failure analysis engineers on silicon and package level fault isolation as well as electrical failure analysis and repair of semiconductor devices. His experience in the semiconductor industry spans over two decades with experience not only in physical and electrical failure analysis but also in the areas of process development and process control and diagnostics. David holds a bachelor's degree in Chemical Engineering from UC Berkeley and an MBA from California State University.